Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/073,756	YAMADA ET AL.	
Examiner	Art Unit	

Binh Q. Nguyen

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	SEAR	CHED	
Class	Subclass	Date	Examiner
370	537	10/26/2005	BQN
370	466	10/26/2005	BQN
370	395.51	10/26/2005	BQN
359	125	10/26/2005	BQN
359	124	10/28/2005	BQN
359	110	10/28/2005	BQN
370	347	10/28/2005	BQN
370	242-250	10/28/2005	BQN

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	10/26/2005	BQN
Consulted with Wellington Chin	10/27/2005	BQN
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